

K6F2008V2E Family

CMOS SRAM

Document Title

256Kx8 bit Super Low Power and Low Voltage Full CMOS Static RAM

Revision History

| <u>Revision No.</u> | <u>History</u> | <u>Draft Date</u> | <u>Remark</u> |
|---------------------|--|--------------------|---------------|
| 0.0 | Initial draft | July 19 , 2001 | Preliminary |
| 1.0 | Finalize | September 27, 2001 | Final |
| 1.1 | Revised - Added Lead Free(LF) product for 32-TSOP1-0813.4F(LF) package. | May 13, 2003 | Final |

256Kx8 bit Super Low Power and Low Voltage Full CMOS Static RAM

FEATURES

- Process Technology: Full CMOS
- Organization: 256Kx8
- Power Supply Voltage: 3.0 ~ 3.6V
- Low Data Retention Voltage: 1.5V(Min)
- Three State Outputs
- Package Type: 32-TSOP1-0813.4F, 32-TSOP1-0813.4F(LF)

GENERAL DESCRIPTION

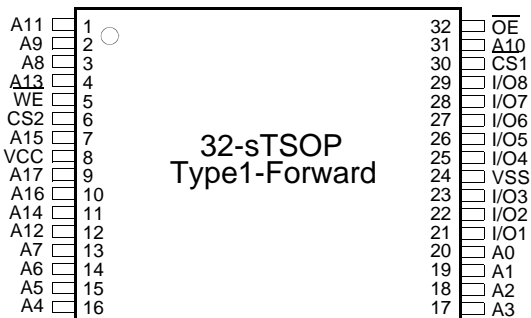
The K6F2008V2E families are fabricated by SAMSUNG's advanced Full CMOS process technology. The families support industrial temperature ranges for user flexibility of system design. The families also supports low data retention voltage for battery back-up operation with low data retention current.

PRODUCT FAMILY

| Product Family | Operating Temperature | Vcc Range | Speed(ns) | Power Dissipation | | PKG Type |
|----------------|-----------------------|-----------|-----------------------|----------------------------------|------------------------------------|--|
| | | | | Standby (I _{SB1} , Typ) | Operating (I _{CC1} , Max) | |
| K6F2008V2E-F | Industrial(-40~85°C) | 3.0~3.6V | 55 ¹ /70ns | 0.5μA ² | 3mA | 32-TSOP1-0813.4F 32-TSOP1-0813.4F(LF) |

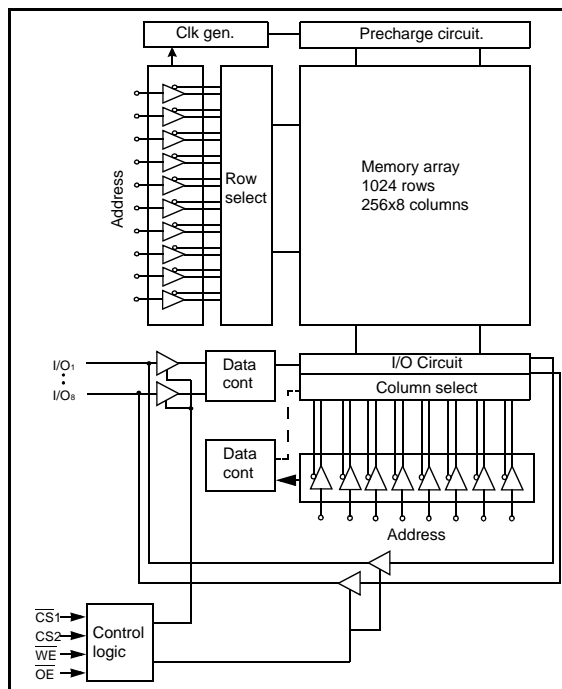
1. The parameter is measured with 30pF test load.
2. Typical values are measured at V_{CC}=3.3V, T_A=25°C and not 100% tested.

PIN DESCRIPTION



| Name | Function | Name | Function |
|-----------------------------------|--------------------|------------------------------------|---------------------|
| CS ₁ , CS ₂ | Chip Select Input | I/O ₁ ~I/O ₈ | Data Inputs/Outputs |
| OE | Output Enable | V _{cc} | Power |
| WE | Write Enable Input | V _{ss} | Ground |
| A ₀ ~A ₁₇ | Address Inputs | DNU | Do Not Use |

FUNCTIONAL BLOCK DIAGRAM



PRODUCT LIST

| Industrial Temperature Products(-40~85°C) | |
|---|---------------------------------|
| Part Name | Function |
| K6F2008V2E-YF55 | 32-sTSOP1-F, 55ns, 3.3V, LL |
| K6F2008V2E-YF70 | 32-sTSOP1-F, 70ns, 3.3V, LL |
| K6F2008V2E-LF55 | 32-sTSOP1-F(LF), 55ns, 3.3V, LL |
| K6F2008V2E-LF70 | 32-sTSOP1-F(LF), 70ns, 3.3V, LL |

FUNCTIONAL DESCRIPTION

| CS ₁ | CS ₂ | OE | WE | I/O | Mode | Power |
|-----------------|-----------------|-----------------|-----------------|--------|----------------|---------|
| H | X ¹⁾ | X ¹⁾ | X ¹⁾ | High-Z | Deselected | Standby |
| X ¹⁾ | L | X ¹⁾ | X ¹⁾ | High-Z | Deselected | Standby |
| L | H | H | H | High-Z | Output Disable | Active |
| L | H | L | H | Dout | Read | Active |
| L | H | X ¹⁾ | L | Din | Write | Active |

1. X means don't care (Must be high or low states)

ABSOLUTE MAXIMUM RATINGS¹⁾

| Item | Symbol | Ratings | Unit | Remark |
|---------------------------------------|-----------------------------------|-------------------------------|------|--------------|
| Voltage on any pin relative to Vss | V _{IN} ,V _{OUT} | -0.2 to V _{CC} +0.5V | V | |
| Voltage on Vcc supply relative to Vss | V _{CC} | -0.2 to 4.6V | V | |
| Power Dissipation | P _D | 1.0 | W | |
| Storage temperature | T _{STG} | -65 to 150 | °C | |
| Operating Temperature | T _A | -40 to 85 | °C | K6F2008V2E-F |

1. Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Functional operation should be restricted to recommended operating condition. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

RECOMMENDED DC OPERATING CONDITIONS¹⁾

| Item | Symbol | Min | Typ. | Max | Unit |
|--------------------|-----------------|--------------------|------|------------------------------------|------|
| Supply voltage | V _{CC} | 3.0 | 3.3 | 3.6 | V |
| Ground | V _{SS} | 0 | 0 | 0 | V |
| Input high voltage | V _{IH} | 2.2 | - | V _{CC} +0.2 ²⁾ | V |
| Input low voltage | V _{IL} | -0.2 ³⁾ | - | 0.6 | V |

Note:

1. Industrial Product: T_A=-40 to 85°C, unless otherwise specified.
2. Overshoot: V_{CC}+2.0V in case of pulse width≤20ns.
3. Undershoot: -2.0V in case of pulse width≤20ns.
4. Overshoot and undershoot are sampled, not 100% tested.

CAPACITANCE¹⁾ (f=1MHz, T_A=25°C)

| Item | Symbol | Test Condition | Min | Max | Unit |
|--------------------------|-----------------|---------------------|-----|-----|------|
| Input capacitance | C _{IN} | V _{IN} =0V | - | 8 | pF |
| Input/Output capacitance | C _{IO} | V _{IO} =0V | - | 10 | pF |

1. Capacitance is sampled, not 100% tested

DC AND OPERATING CHARACTERISTICS

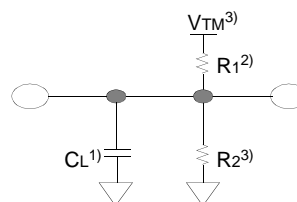
| Item | Symbol | Test Conditions | Min | Typ ¹⁾ | Max | Unit |
|---------------------------|------------------|--|-----|-------------------|-----|------|
| Input leakage current | I _{LI} | V _{IN} =V _{SS} to V _{CC} | -1 | - | 1 | μA |
| Output leakage current | I _{LO} | $\overline{CS}_1=V_{IH}$ or $\overline{CS}_2=V_{IL}$ or $\overline{OE}=V_{IH}$ or $\overline{WE}=V_{IL}$, V _{IO} =V _{SS} to V _{CC} | -1 | - | 1 | μA |
| Average operating current | I _{CC1} | Cycle time=1μs, 100% duty, I _{IO} =0mA, $\overline{CS}_1 \leq 0.2V$, $\overline{CS}_2 \geq V_{CC}-0.2V$, V _{IN} ≤0.2V or V _{IN} ≥V _{CC} -0.2V | - | - | 3 | mA |
| | I _{CC2} | Cycle time=Min, 100% duty, I _{IO} =0mA, $\overline{CS}_1=V_{IL}$, $\overline{CS}_2=V_{IH}$, V _{IN} =V _{IL} or V _{IH} | - | - | 35 | mA |
| Output low voltage | V _{OL} | I _{OL} =2.1mA | - | - | 0.4 | V |
| Output high voltage | V _{OH} | I _{OH} =-1.0mA | 2.4 | - | - | V |
| Standby Current(CMOS) | I _{SB1} | Other inputs=V _{SS} to V _{CC} 1) $\overline{CS}_1 \geq V_{CC}-0.2V$, $\overline{CS}_2 \geq V_{CC}-0.2V$ (\overline{CS}_1 controlled) or 2) $0V \leq \overline{CS}_2 \leq 0.2V$ \overline{CS}_2 controlled) | - | 0.5 | 10 | μA |

1. Typical value are measured at V_{CC}=3.3V, T_A=25°C, and not 100% tested.

AC OPERATING CONDITIONS

TEST CONDITIONS (Test Load and Test Input/Output Reference)

Input pulse level: 0.4 to 2.2V
 Input rising and falling time: 5ns
 Input and output reference voltage: 1.5V
 Output load (See right): $C_L=100\text{pF}+1\text{TTL}$
 $C_L=30\text{pF}+1\text{TTL}$



1. Including scope and jig capacitance
2. $R_1=3070\Omega$, $R_2=3150\Omega$
3. $V_{TM}=2.8\text{V}$

AC CHARACTERISTICS ($V_{CC}=3.0\sim 3.6\text{V}$, $T_A=-40$ to 85°C)

| Parameter List | Symbol | Speed Bins | | | | Units | |
|----------------|---------------------------------|--------------------|-----|------|-----|-------|----|
| | | 55ns ¹⁾ | | 70ns | | | |
| | | Min | Max | Min | Max | | |
| Read | Read Cycle Time | t _{RC} | 55 | - | 70 | - | ns |
| | Address Access Time | t _{AA} | - | 55 | - | 70 | ns |
| | Chip Select to Output | t _{CO} | - | 55 | - | 70 | ns |
| | Output Enable to Valid Output | t _{OE} | - | 25 | - | 35 | ns |
| | Chip Select to Low-Z Output | t _{LZ} | 10 | - | 10 | - | ns |
| | Output Enable to Low-Z Output | t _{OLZ} | 5 | - | 5 | - | ns |
| | Chip Disable to High-Z Output | t _{HZ} | 0 | 20 | 0 | 25 | ns |
| | Output Disable to High-Z Output | t _{OHZ} | 0 | 20 | 0 | 25 | ns |
| | Output Hold from Address Change | t _{OH} | 10 | - | 10 | - | ns |
| Write | Write Cycle Time | t _{WC} | 55 | - | 70 | - | ns |
| | Chip Select to End of Write | t _{CW} | 45 | - | 60 | - | ns |
| | Address Set-up Time | t _{AS} | 0 | - | 0 | - | ns |
| | Address Valid to End of Write | t _{AW} | 45 | - | 60 | - | ns |
| | Write Pulse Width | t _{WP} | 40 | - | 50 | - | ns |
| | Write Recovery Time | t _{WR} | 0 | - | 0 | - | ns |
| | Write to Output High-Z | t _{WHZ} | 0 | 20 | 0 | 20 | ns |
| | Data to Write Time Overlap | t _{DW} | 25 | - | 30 | - | ns |
| | Data Hold from Write Time | t _{DH} | 0 | - | 0 | - | ns |
| | End Write to Output Low-Z | t _{OW} | 5 | - | 5 | - | ns |

1. The parameter is measured with 30pF test load.

DATA RETENTION CHARACTERISTICS

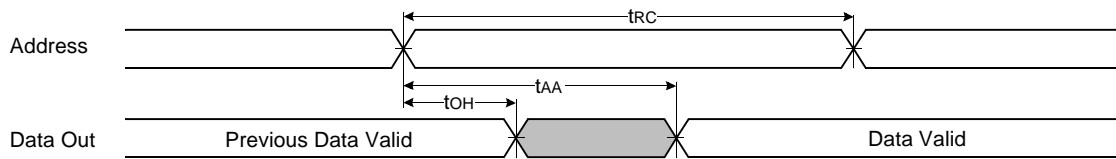
| Item | Symbol | Test Condition | Min | Typ | Max | Unit |
|------------------------------------|------------------|--|-----------------|-------------------|-----|------|
| V _{CC} for data retention | V _{DR} | $\overline{CS}_1 \geq V_{CC}-0.2\text{V}^{(1)}$ | 1.5 | - | 3.6 | V |
| Data retention current | I _{DR} | $V_{CC}=1.5\text{V}$, $\overline{CS}_1 \geq V_{CC}-0.2\text{V}^{(1)}$ | - | 0.2 ²⁾ | 2 | μA |
| Data retention set-up time | t _{SDR} | See data retention waveform | 0 | - | - | ns |
| Recovery time | t _{RDR} | | t _{RC} | - | - | |

1. $\overline{CS}_1 \geq V_{CC}-0.2\text{V}$, $\overline{CS}_2 \geq V_{CC}-0.2\text{V}$ (\overline{CS}_1 controlled) or $\overline{CS}_2 \leq 0.2\text{V}$ (\overline{CS}_2 controlled).

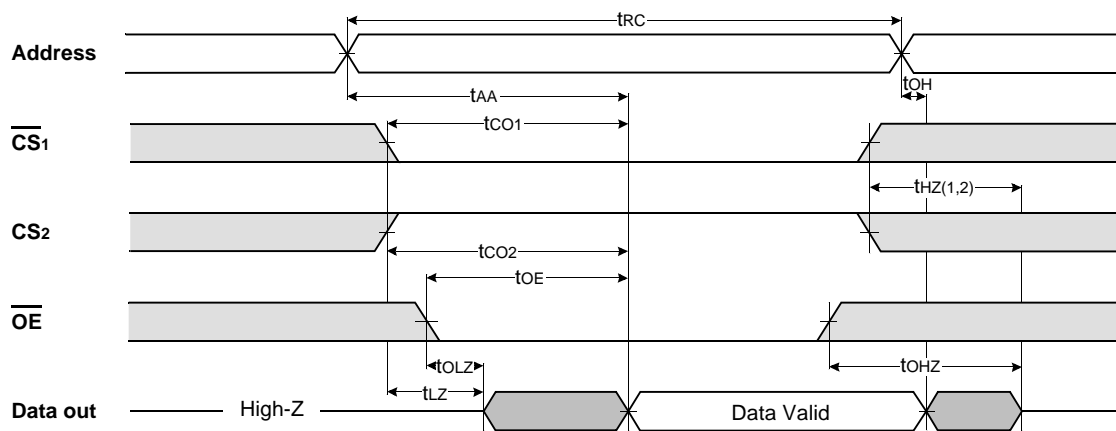
2. Typical values are measured at $T_A=25^\circ\text{C}$ and not 100% tested.

TIMING DIAGRAMS

TIMING WAVEFORM OF READ CYCLE(1) (Address Controlled, $\overline{CS1}=\overline{OE}=V_{IL}$, $\overline{WE}=V_{IH}$)



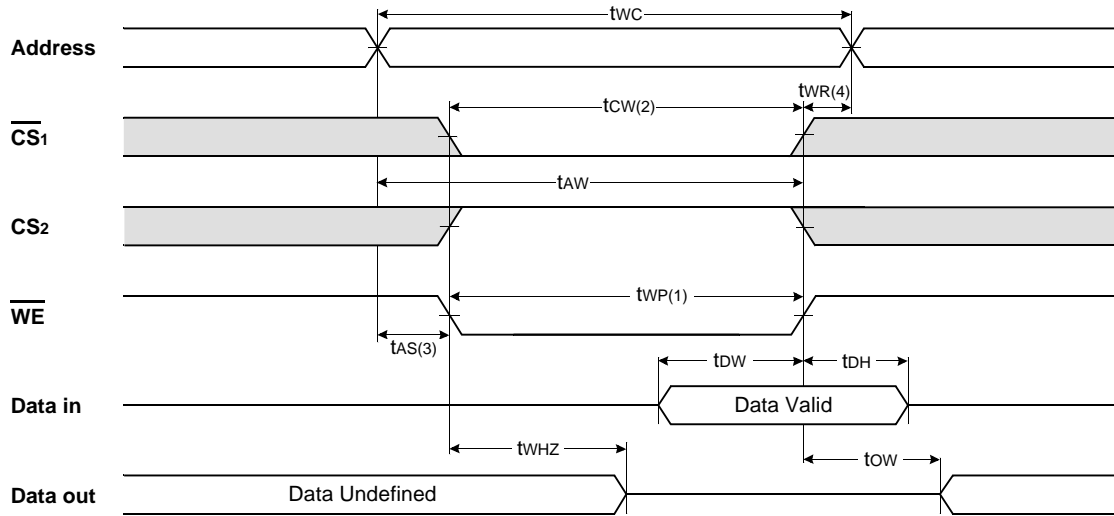
TIMING WAVEFORM OF READ CYCLE(2) ($\overline{WE}=V_{IH}$)



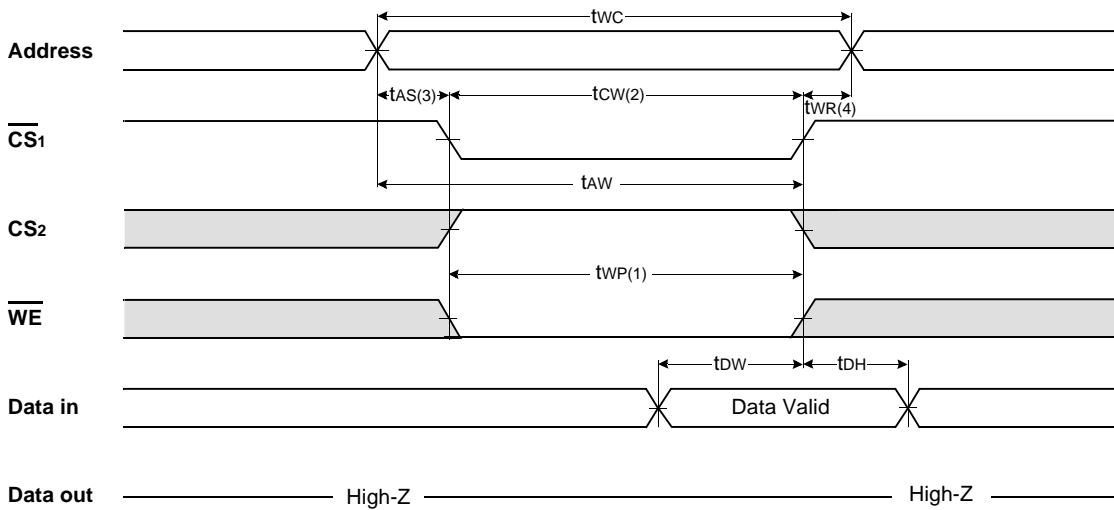
NOTES (READ CYCLE)

1. t_{HZ} and t_{OHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referenced to output voltage levels.
2. At any given temperature and voltage condition, $t_{HZ}(\text{Max.})$ is less than $t_{LZ}(\text{Min.})$ both for a given device and from device to device interconnection.

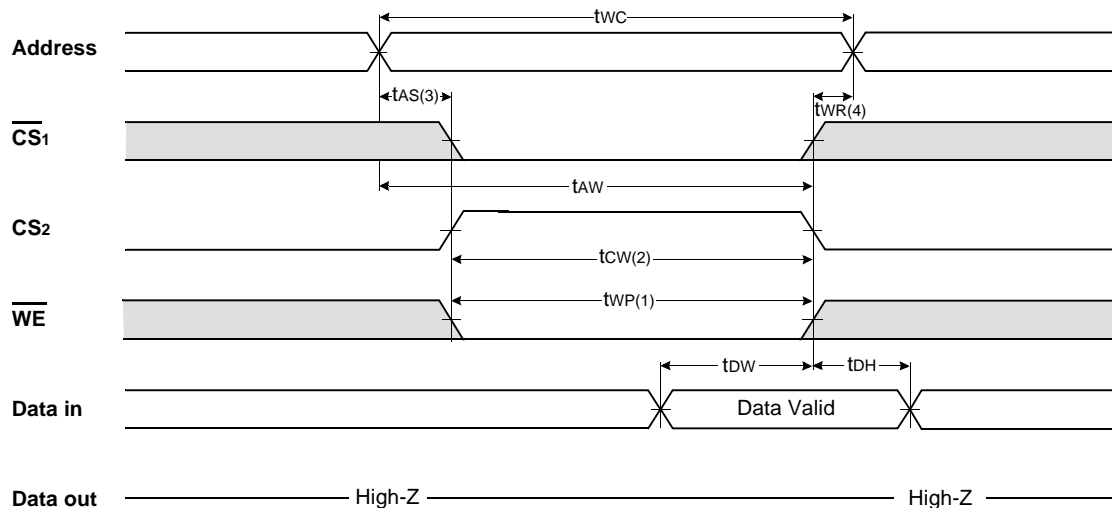
TIMING WAVEFORM OF WRITE CYCLE(1) (\overline{WE} Controlled)



TIMING WAVEFORM OF WRITE CYCLE(2) ($\overline{CS1}$ Controlled)



TIMING WAVEFORM OF WRITE CYCLE(3) (CS₂ Controlled)

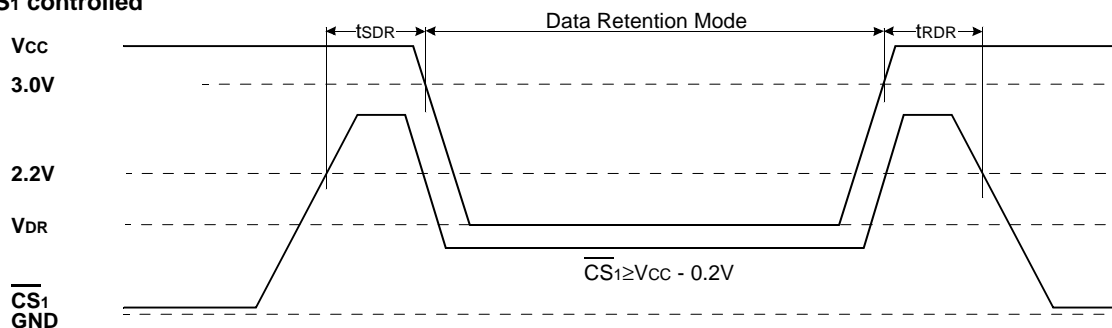


NOTES (WRITE CYCLE)

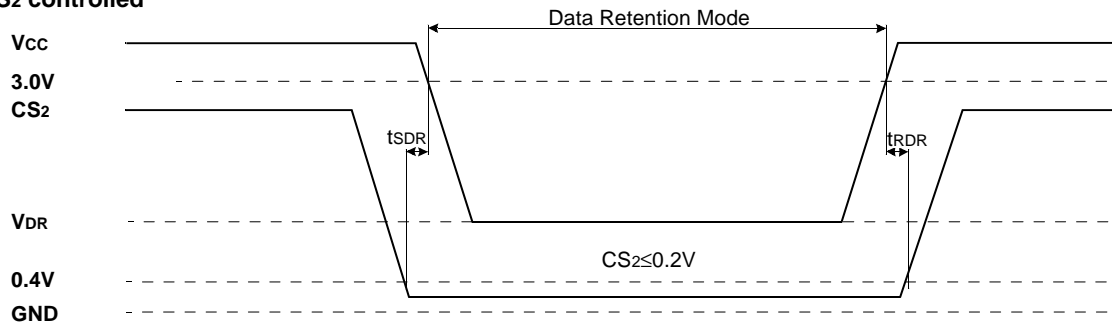
1. A write occurs during the overlap of a low \overline{CS}_1 , a high CS_2 and a low \overline{WE} . A write begins at the latest transition among \overline{CS}_1 goes low, CS_2 going high and \overline{WE} going low : A write end at the earliest transition among \overline{CS}_1 going high, CS_2 going low and \overline{WE} going high, t_{WP} is measured from the beginning of write to the end of write.
2. t_{CW} is measured from the \overline{CS}_1 going low or CS_2 going high to the end of write.
3. t_{AS} is measured from the address valid to the beginning of write.
4. t_{WR} is measured from the end of write to the address change.

DATA RETENTION WAVE FORM

\overline{CS}_1 controlled



CS₂ controlled



PACKAGE DIMENSIONS

Units: millimeters(inches)

32 PIN THIN SMALL OUTLINE PACKAGE TYPE I (0813.4F)

